

Description

TheVSM60N20uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

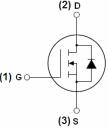
General Features

- V_{DS} =200V, I_{D} =60A $R_{DS(ON)}$ <32m Ω @ V_{GS} =10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply





Schematic Diagram

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|----------|----------------|-----------|------------|----------|
| VSM60N20-TC | VSM60N20 | TO-220C | - | - | - |

Absolute Maximum Ratings (T_c=25 ℃ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|--|-----------------------|------------|------------|
| Drain-Source Voltage | V _{DS} | 200 | V |
| Gate-Source Voltage | V _G s | ±20 | V |
| Drain Current-Continuous | I _D | 60 | А |
| Drain Current-Continuous(T _C =100°C) | I _D (100℃) | 42 | Α |
| Pulsed Drain Current | I _{DM} | 280 | Α |
| Maximum Power Dissipation | P _D | 285 | W |
| Derating factor | | 1.9 | W/℃ |
| Single pulse avalanche energy (Note 5) | E _{AS} | 225 | mJ |
| Operating Junction and Storage Temperature Range | T_{J},T_{STG} | -55 To 175 | $^{\circ}$ |



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Thermal Characteristic

| Thermal Resistance,Junction-to-Case ^(Note 2) | R _{eJC} | 0.53 | °C/W | |
|---|------------------|------|------|--|
|---|------------------|------|------|--|

Electrical Characteristics (T_C=25°C unless otherwise noted)

| Parameter | Symbol | Condition | Min | Тур | Max | Unit |
|------------------------------------|---------------------|--|-----|------|------|------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | V _{GS} =0V I _D =250µA | 200 | 220 | - | V |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =200V,V _{GS} =0V | - | - | 1 | μA |
| Gate-Body Leakage Current | I _{GSS} | V _{GS} =±20V,V _{DS} =0V | - | - | ±100 | nA |
| On Characteristics (Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}$, $I_{D}=250\mu A$ | 2 | 3.2 | 4 | V |
| Drain-Source On-State Resistance | R _{DS(ON)} | V _{GS} =10V, I _D =20A | - | 24 | 32 | mΩ |
| Forward Transconductance | g FS | V _{DS} =5V,I _D =30A | 40 | - | - | S |
| Dynamic Characteristics (Note4) | | | | | | |
| Input Capacitance | C _{lss} | V _{DS} =50V,V _{GS} =0V, | - | 6200 | - | PF |
| Output Capacitance | C _{oss} | | - | 950 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | F=1.0MHz | - | 460 | - | PF |
| Switching Characteristics (Note 4) | | | • | | | • |
| Turn-on Delay Time | t _{d(on)} | | - | 33 | - | nS |
| Turn-on Rise Time | t _r | V_{DD} =100V, R_{L} =15 Ω V_{GS} =10V, R_{G} =2.5 Ω | - | 20 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 21 | - | nS |
| Turn-Off Fall Time | t _f | | - | 31 | - | nS |
| Total Gate Charge | Qg | V _{DS} =100V,I _D =30A, | - | 130 | | nC |
| Gate-Source Charge | Q _{gs} | | - | 36 | | nC |
| Gate-Drain Charge | Q_{gd} | V _{GS} =10V | - | 46 | | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage (Note 3) | V _{SD} | V _{GS} =0V,I _S =30A | - | | 1.2 | V |
| Diode Forward Current (Note 2) | Is | | - | - | 60 | Α |
| Reverse Recovery Time | t _{rr} | TJ = 25°C, IF = 30A | - | 42 | | nS |
| Reverse Recovery Charge | Qrr | di/dt = 100A/µs ^(Note3) | - | 66 | | nC |
| Forward Turn-On Time | t _{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

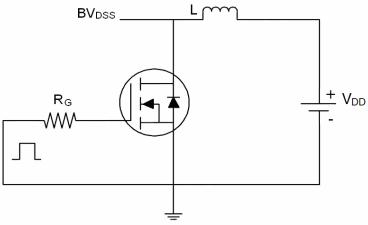
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production
- 5. E_{AS} condition: j=25 $^{\circ}\text{C}\,\text{,V}_{DD}\text{=}50\text{V},\text{V}_{G}\text{=}10\text{V},\text{L=}0.5\text{mH,Rg=}25\Omega$

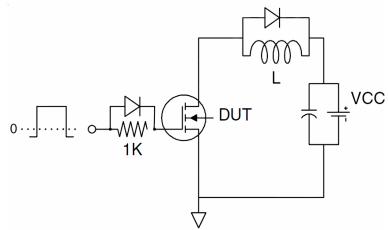


Test Circuit

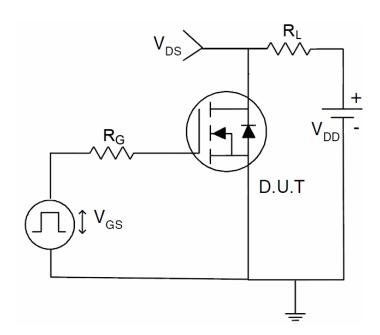
1) E_{AS} test Circuits



2) Gate charge test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

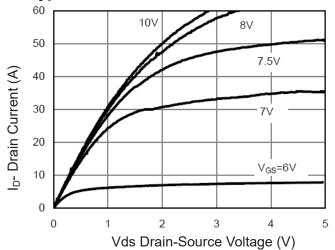


Figure 1 Output Characteristics

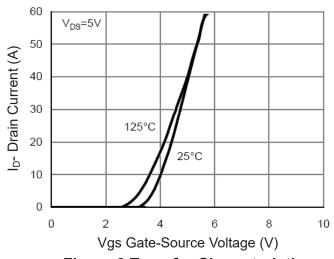


Figure 2 Transfer Characteristics

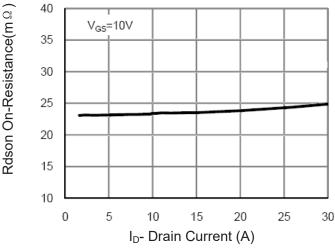


Figure 3 Rdson- Drain Current

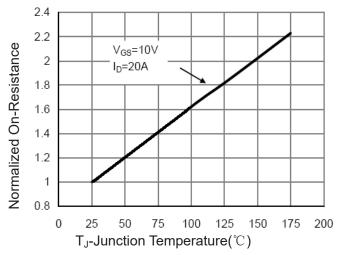


Figure 4 Rdson-Junction Temperature

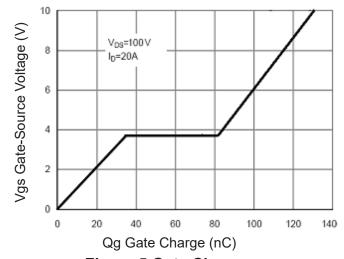


Figure 5 Gate Charge

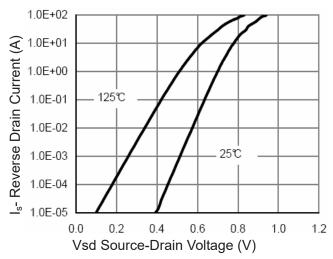


Figure 6 Source- Drain Diode Forward



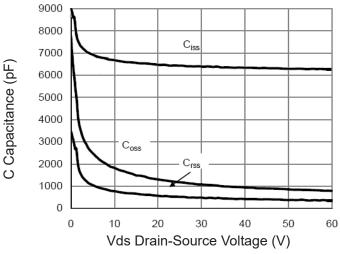


Figure 7 Capacitance vs Vds

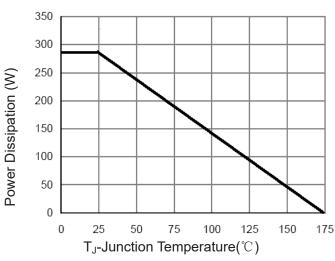


Figure 9 Power De-rating

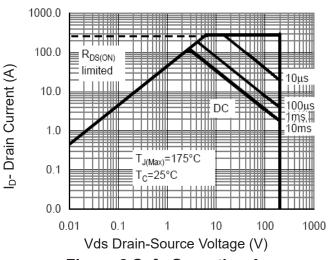


Figure 8 Safe Operation Area

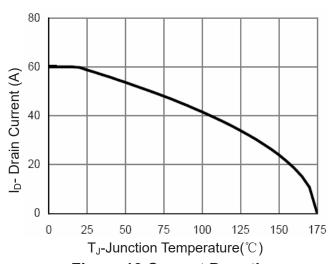


Figure 10 Current De-rating

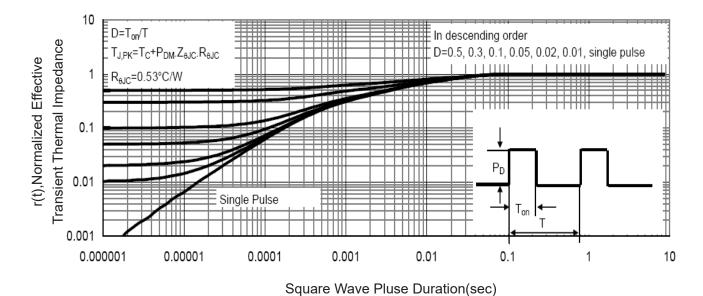


Figure 11 Normalized Maximum Transient Thermal Impedance